

Notice of References Cited

Application/Control No.

10/501,429

Applicant(s)/Patent Under
Reexamination
TIEKE ET AL.

Examiner

TAN X. DINH

Art Unit

2627

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2006/0240357 A1	10-2006	Martens et al.	430/270.11
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NON-PATENT DOCUMENTS

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